

Lecture 18

The Bipolar Junction Transistor (II)

Regimes of Operation

Outline

- Regimes of operation
- Large-signal equivalent circuit model
- Output characteristics

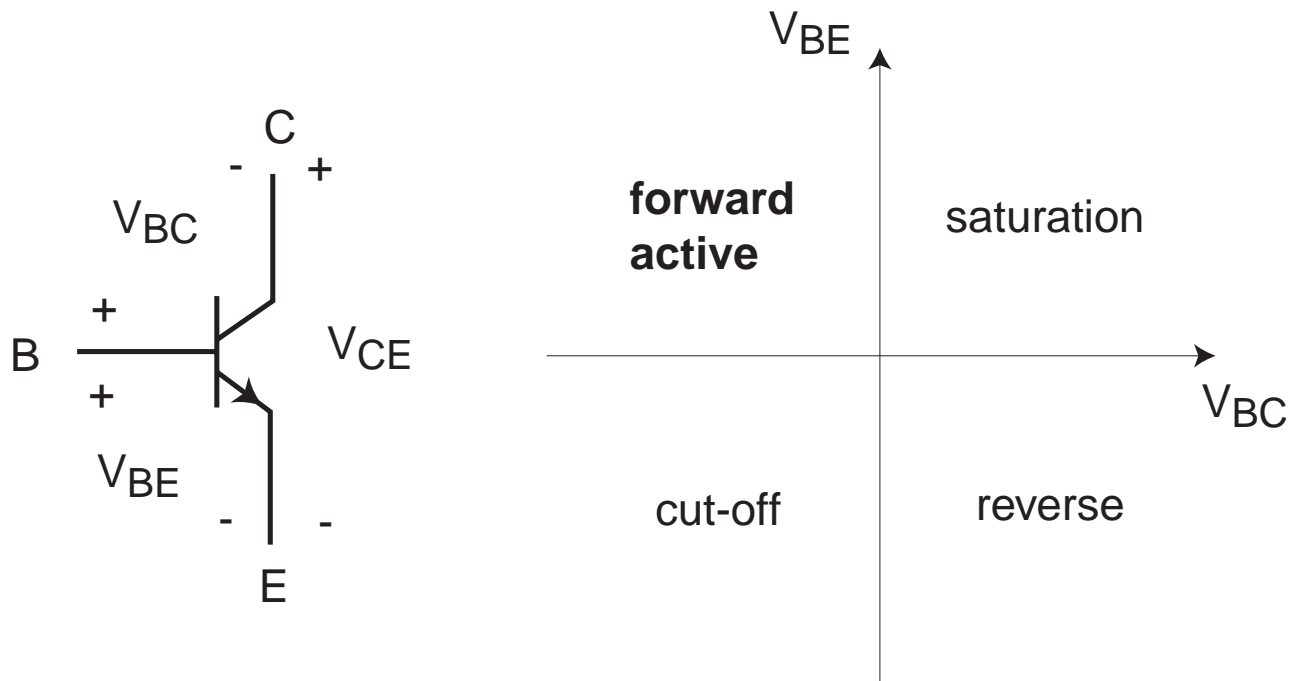
Reading Assignment:

Howe and Sodini; Chapter 7, Sections 7.3, 7.4 & 7.5

Announcement:

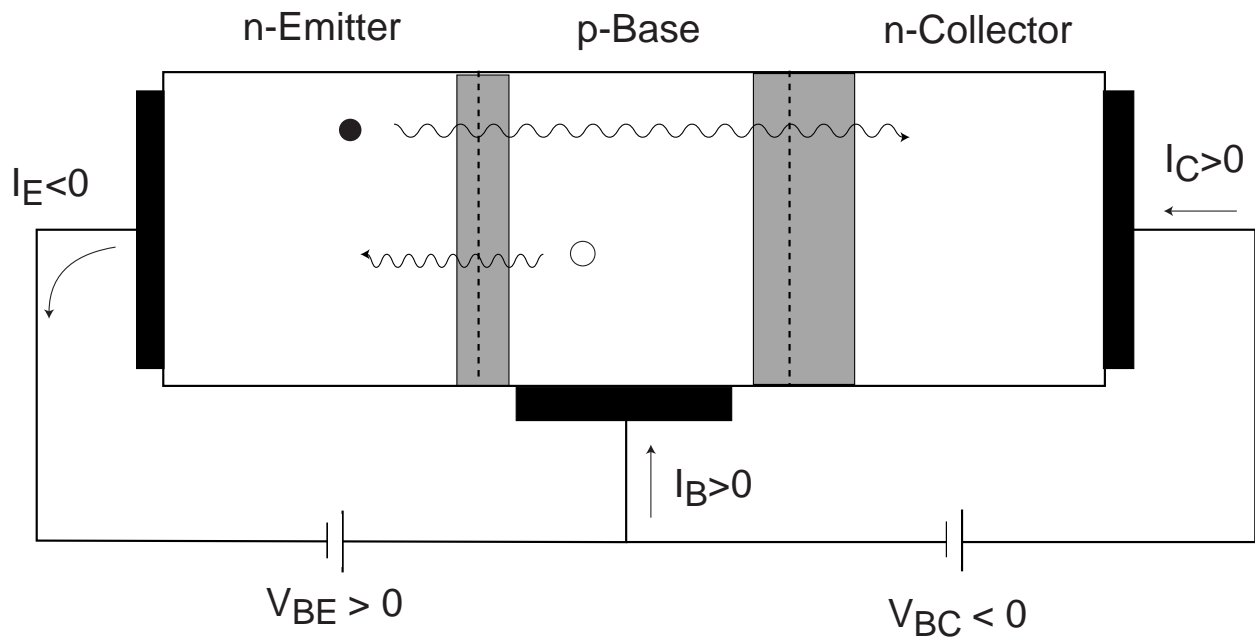
Quiz #2: April 25, 7:30-9:30 PM at Walker. Calculator Required. Open book.

1. BJT: Regions of Operation

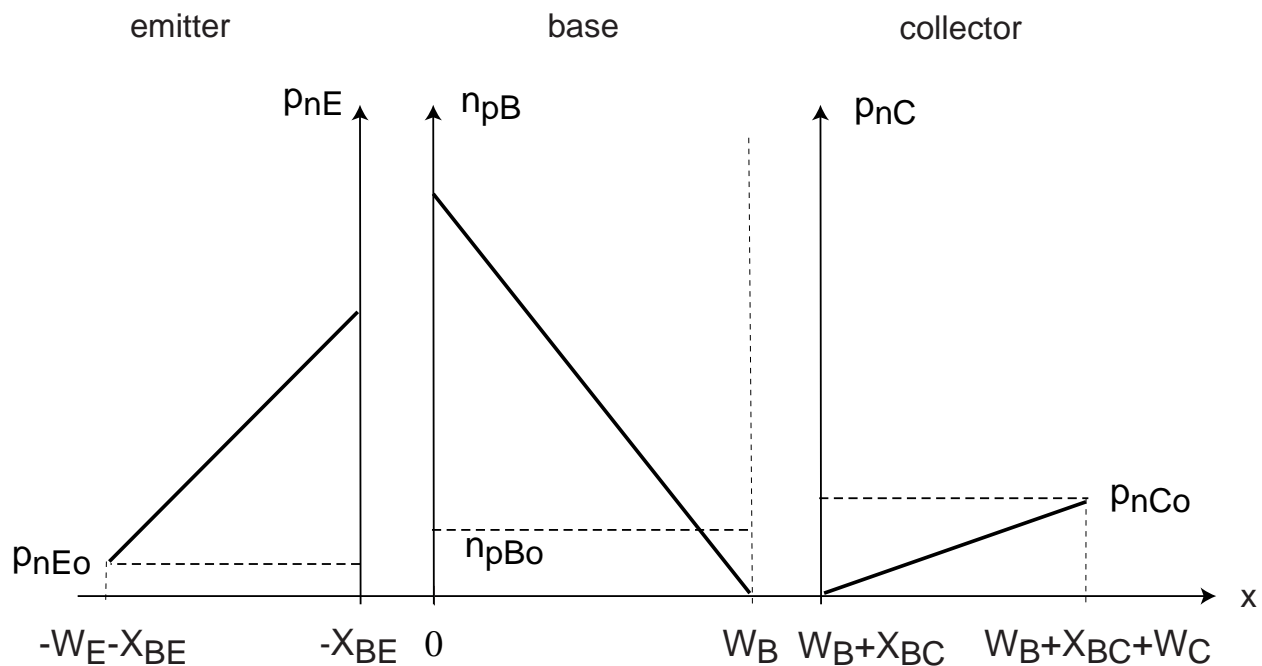


- **Forward active**: device has high voltage gain and high β ;
- **Reverse active**: poor β ; **not useful**;
- **Cut-off**: negligible current: nearly an open circuit;
- **Saturation**: device is flooded with minority carriers;
 - \Rightarrow takes time to get out of saturation

Forward-Active Regime: $V_{BE} > 0$, $V_{BC} < 0$



Minority Carrier profiles (*not to scale*):



Forward-Active Regime: $V_{BE} > 0, V_{BC} < 0$

- **Emitter** injects **electrons** into **base**, **collector** extracts (collects) **electrons** from **base**:

$$I_C = I_S e^{\left[\frac{V_{BE}}{V_{th}} \right]}, \quad I_S = \frac{qA_E n_{pB0} D_n}{W_B}$$

- **Base** injects **holes** into **emitter**, **holes** recombine at **emitter** contact:

$$I_B = \frac{I_S}{\beta_F} \left[e^{\left[\frac{V_{BE}}{V_{th}} \right]} - 1 \right]; \quad \frac{I_S}{\beta_F} = \frac{qA_E p_{nE0} D_p}{W_E}$$

- **Emitter** current:

$$I_E = -I_C - I_B = -I_S e^{\left[\frac{V_{BE}}{V_{th}} \right]} - \frac{I_S}{\beta_F} \left(e^{\left[\frac{V_{BE}}{V_{th}} \right]} - 1 \right)$$

- State-of-the-art IC BJT's today: $I_S \approx 0.1 - 1 \text{ fA}$
- $\beta_F \approx 50 - 300$.
- β_F hard to control tightly: \Rightarrow circuit design techniques required to be insensitive to variations in β_F .

$$\beta_F = \frac{I_C}{I_B} = \frac{n_{pB0} \cdot \frac{D_n}{W_B}}{p_{nE0} \cdot \frac{D_p}{W_E}} = \frac{N_{dE} D_n W_E}{N_{aB} D_p W_B}$$

Reverse-Active Regime: $V_{BE} < 0$, $V_{BC} > 0$

- **Collector** injects electrons into **base**, **emitter** extracts (collects) electrons from **base**:

$$I_E = I_S e^{\left[\frac{V_{BC}}{V_{th}} \right]}, \quad I_S = \frac{qA_C n_{pB_0} D_n}{W_B}$$

- **Base** injects holes into **collector**, holes recombine at **collector** contact and buried layer:

$$I_B = \frac{I_S}{\beta_R} \left[e^{\left(\frac{V_{BC}}{V_{th}} \right)} - 1 \right]; \quad \frac{I_S}{\beta_R} = \frac{qA_C p_{nC_0} D_p}{W_C}$$

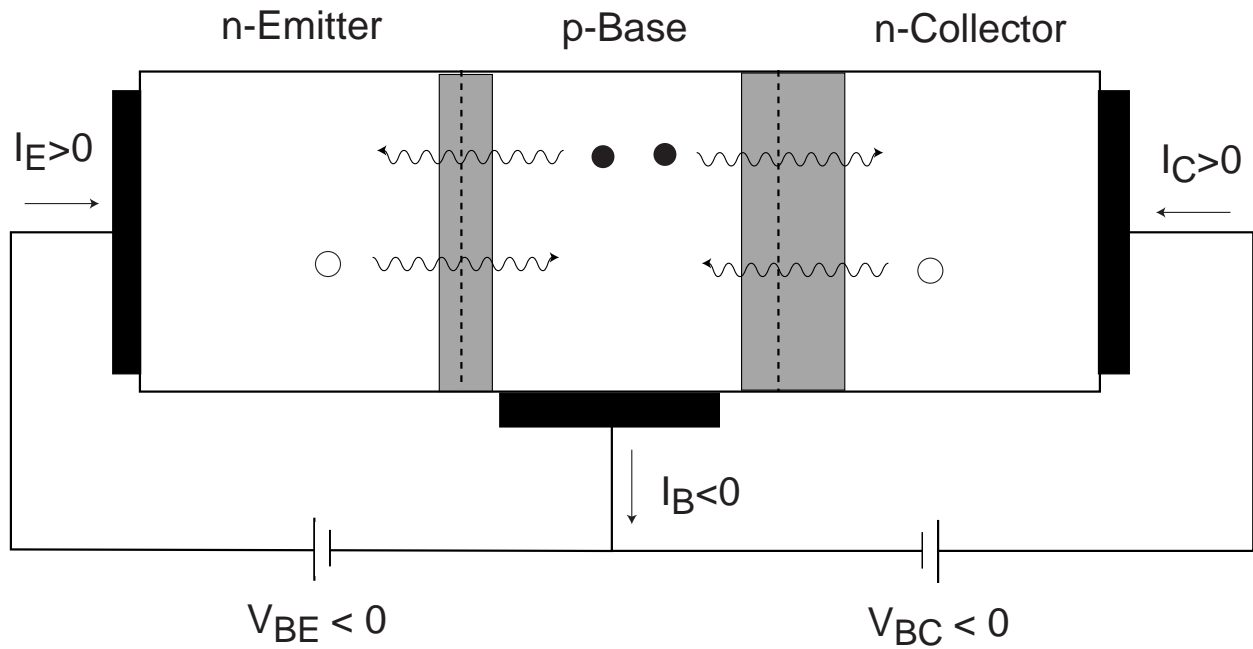
- **Collector** current:

$$I_C = -I_E - I_B = -I_S e^{\left[\frac{V_{BC}}{V_{th}} \right]} - \frac{I_S}{\beta_R} \left(e^{\left[\frac{V_{BC}}{V_{th}} \right]} - 1 \right)$$

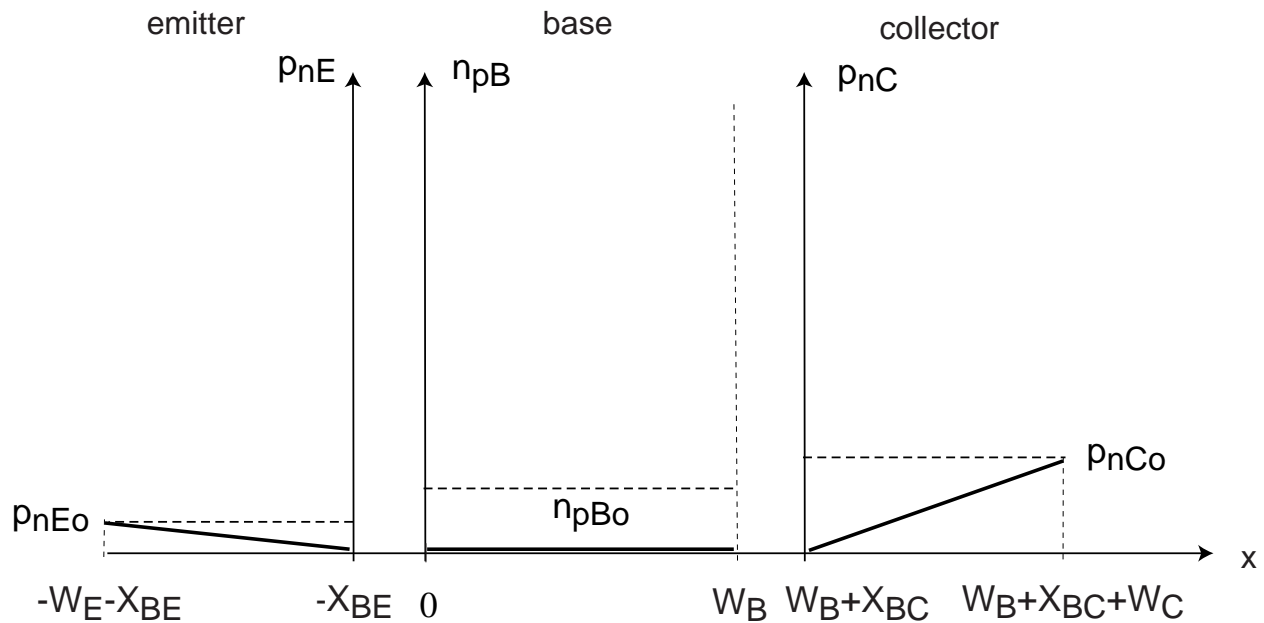
- Typically, $\beta_R \approx 0.1 - 5 \ll \beta_F$.

$$\beta_R = \frac{I_E}{I_B} = \frac{n_{pB_0} \cdot \frac{D_n}{W_B}}{p_{nC_0} \cdot \frac{D_p}{W_C}} = \frac{N_{dC} D_n W_C}{N_{aB} D_p W_B}$$

Cut-Off Regime: $V_{BE} < 0, V_{BC} < 0$



Minority Carrier Profiles (*not to scale*):



Cut-Off Regime: $V_{BE} < 0$, $V_{BC} < 0$

- *Base* extracts holes from *emitter*:

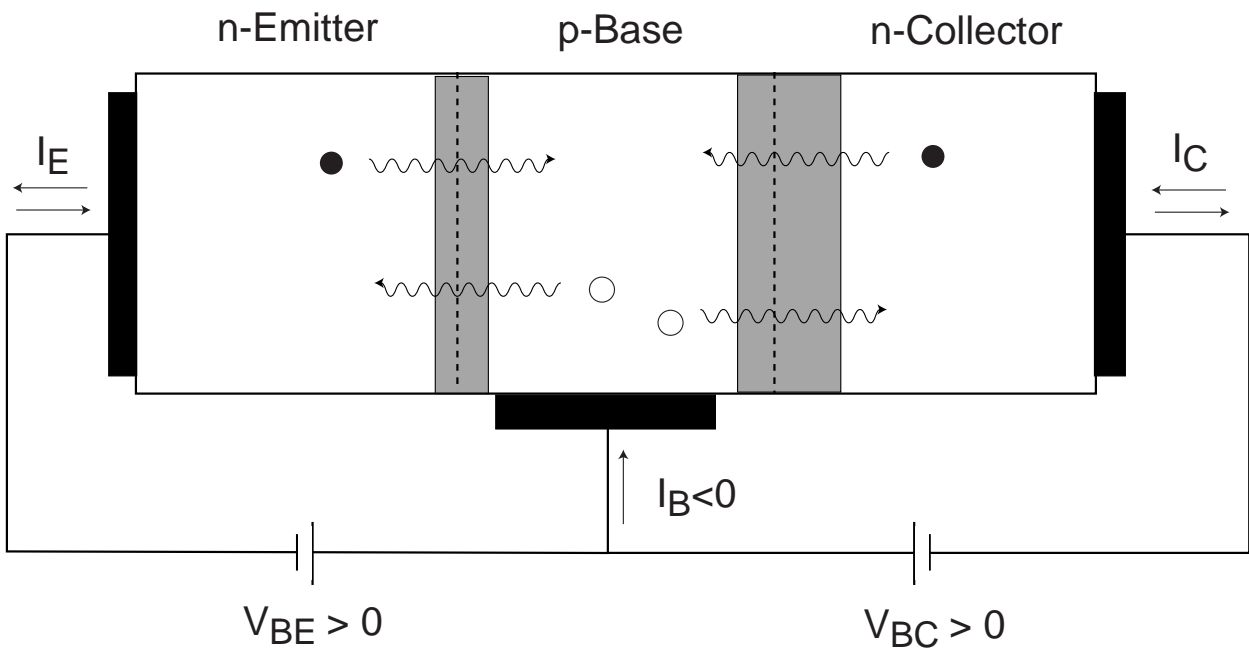
$$I_{B1} = -\frac{I_S}{\beta_F} = -I_E$$

- *Base* extracts holes from *collector*:

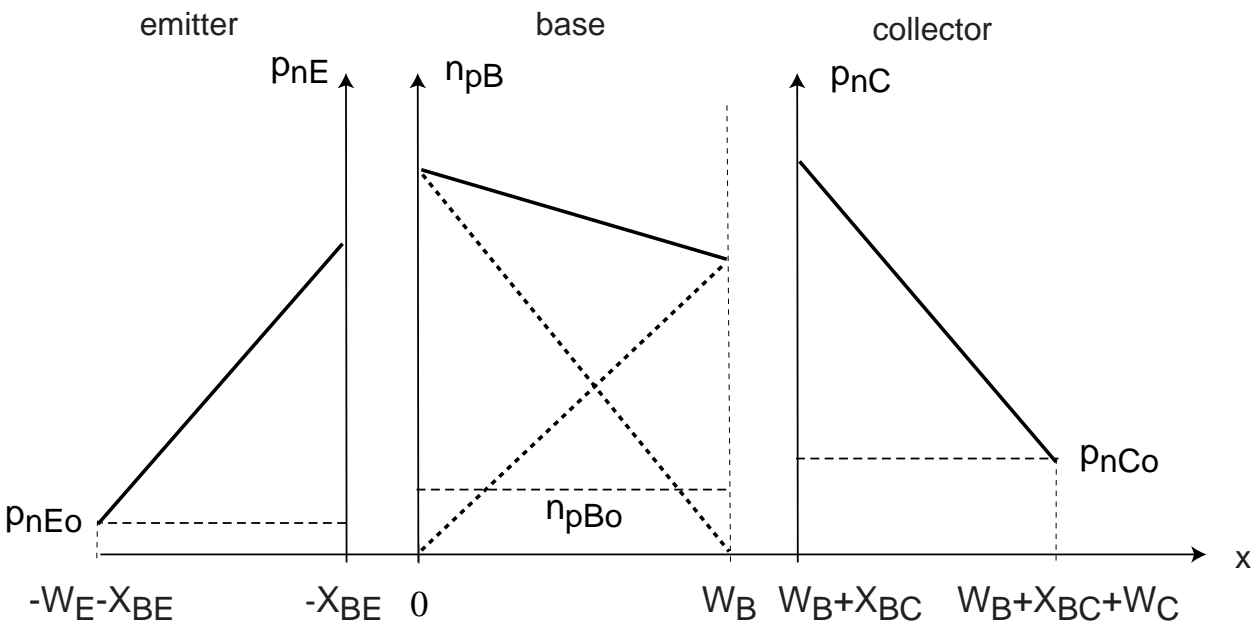
$$I_{B2} = -\frac{I_S}{\beta_R} = -I_C$$

- These are tiny leakage currents ($\approx 10^{-15}$ A).

Saturation Regime: $V_{BE} > 0, V_{BC} > 0$



Minority Carrier profiles (*not to scale*):



Saturation Regime: $V_{BE} > 0, V_{BC} > 0$

Saturation is superposition of forward active + reverse active:

$$I_C = I_S \left(e^{\frac{V_{BE}}{V_{th}}} - e^{\frac{V_{BC}}{V_{th}}} \right) - \frac{I_S}{\beta_R} \left(e^{\frac{V_{BC}}{V_{th}}} - 1 \right)$$

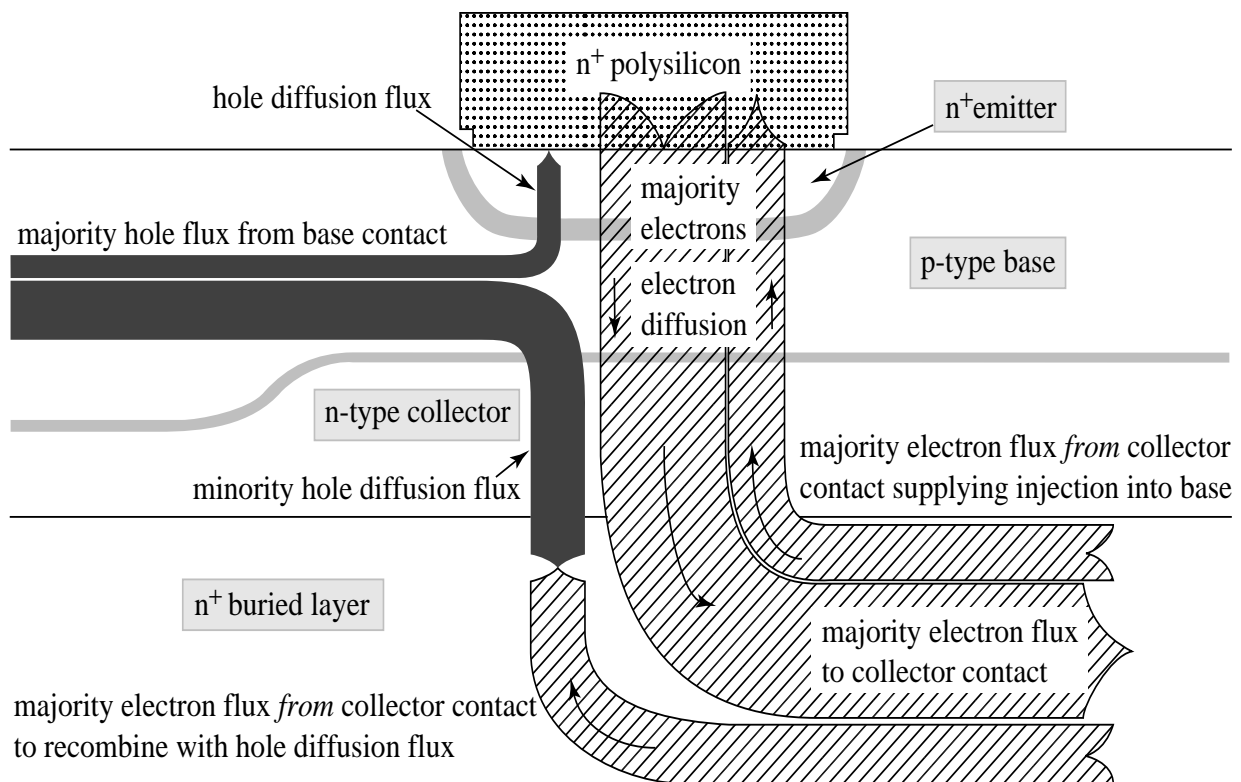
$$I_B = \frac{I_S}{\beta_F} \left[e^{\frac{V_{BE}}{V_{th}}} - 1 \right] + \frac{I_S}{\beta_R} \left[e^{\frac{V_{BC}}{V_{th}}} - 1 \right]$$

$$I_E = -I_S \left[e^{\frac{V_{BE}}{V_{th}}} - e^{\frac{V_{BC}}{V_{th}}} \right] - \frac{I_S}{\beta_F} \left[e^{\frac{V_{BE}}{V_{th}}} - 1 \right]$$

- I_C and I_E can have either sign, depending on relative magnitudes of V_{BE} and V_{BC} and β_F and β_R .

Saturation - The Flux Picture

- Both junctions are injecting and collecting.
- Electrons injected from emitter into base are collected by the collector as in Forward Active case.
- Electrons injected from collector into the base are collected by the emitter as in Reverse Active case.
- Holes injected into emitter recombine at ohmic contact as in Forward Active case.
- Holes injected into collector recombine with electrons in the n^+ buried layer



2. Large-signal equivalent circuit model

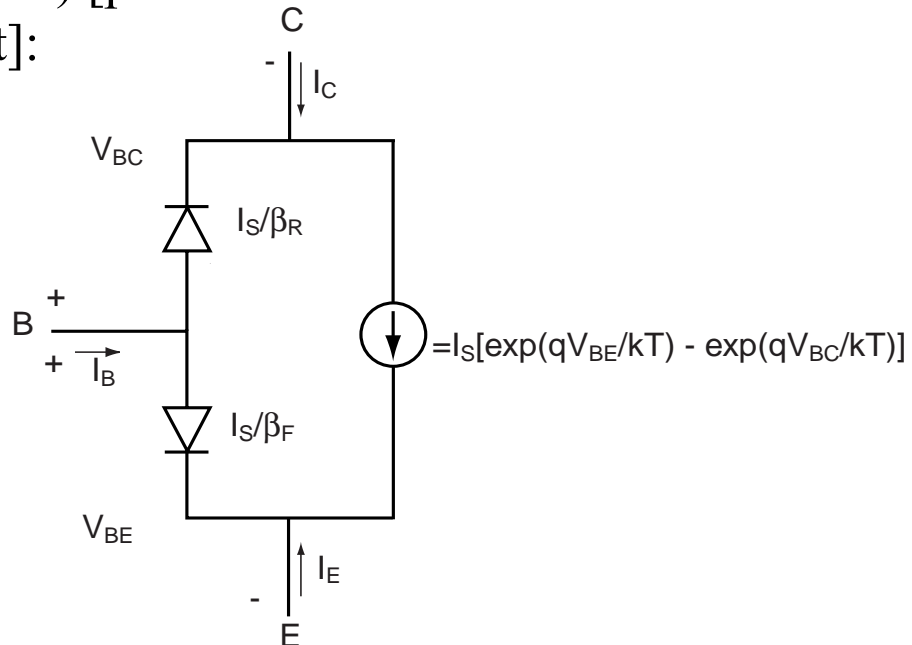
System of equations that describes BJT operation:

$$I_C = I_S \left(e^{\frac{V_{BE}}{V_{th}}} - e^{\frac{V_{BC}}{V_{th}}} \right) - \frac{I_S}{\beta_R} \left(e^{\frac{V_{BC}}{V_{th}}} - 1 \right)$$

$$I_B = \frac{I_S}{\beta_F} \left[e^{\frac{V_{BE}}{V_{th}}} - 1 \right] + \frac{I_S}{\beta_R} \left[e^{\frac{V_{BC}}{V_{th}}} - 1 \right]$$

$$I_E = -I_S \left[e^{\frac{V_{BE}}{V_{th}}} - e^{\frac{V_{BC}}{V_{th}}} \right] - \frac{I_S}{\beta_F} \left[e^{\frac{V_{BE}}{V_{th}}} - 1 \right]$$

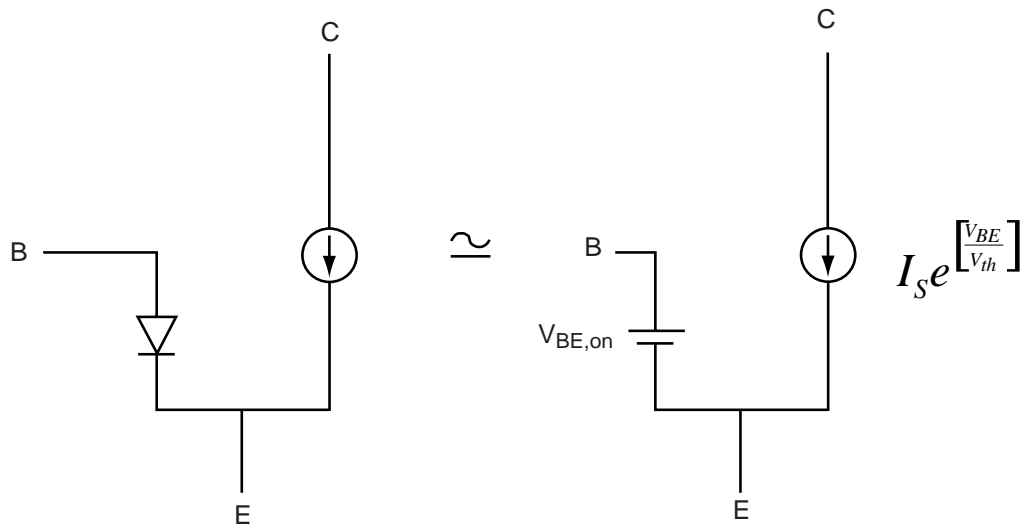
Equivalent-circuit model representation (*non-linear hybrid- π model*) [particular rendition of Ebers-Moll model in text]:



Three parameters in this model: I_S , β_F , and β_R .

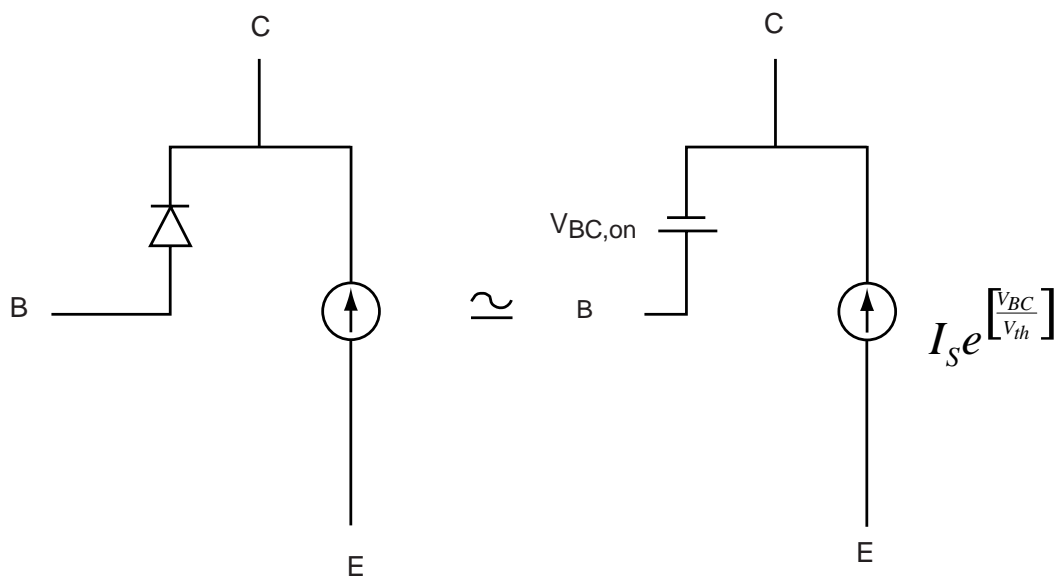
Simplification of equivalent circuit model:

- Forward-active regime:** $V_{BE} > 0$, $V_{BC} < 0$



For today's technology: $V_{BE,on} \approx 0.7$ V. I_B depends on outside circuit.

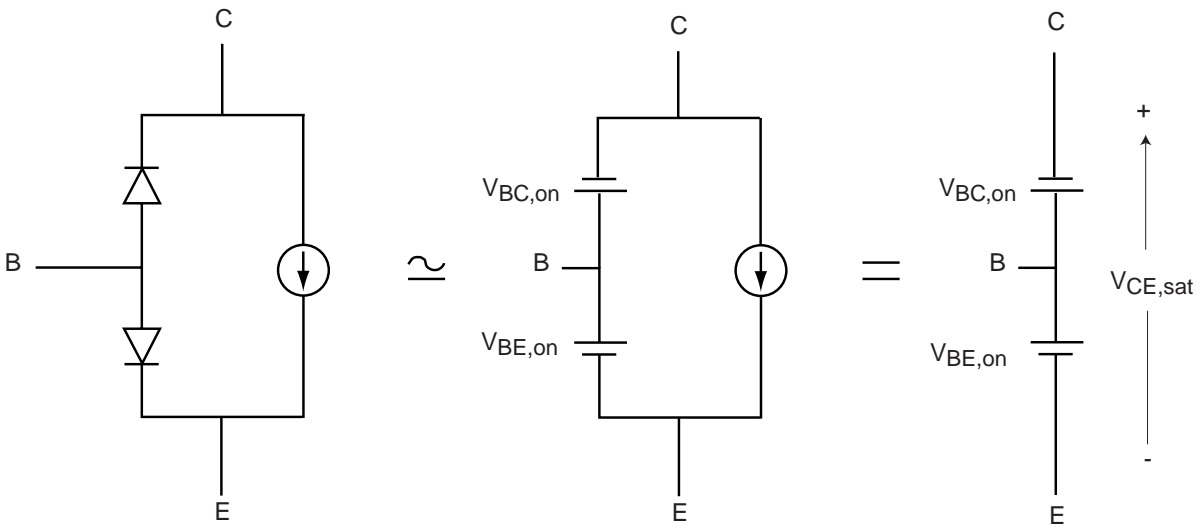
- Reverse-active regime:** $V_{BE} < 0$, $V_{BC} > 0$



For today's technology: $V_{BC,on} \approx 0.6$ V

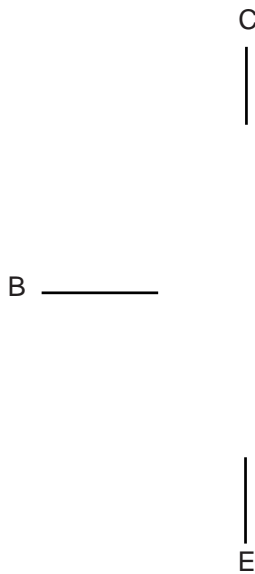
Simplification of equivalent circuit model:

- **Saturation regime:** $V_{BE} > 0$, $V_{BC} > 0$



For today's technology: $V_{CE,sat} \approx 0.1$ V. I_C and I_B depend on outside circuit.

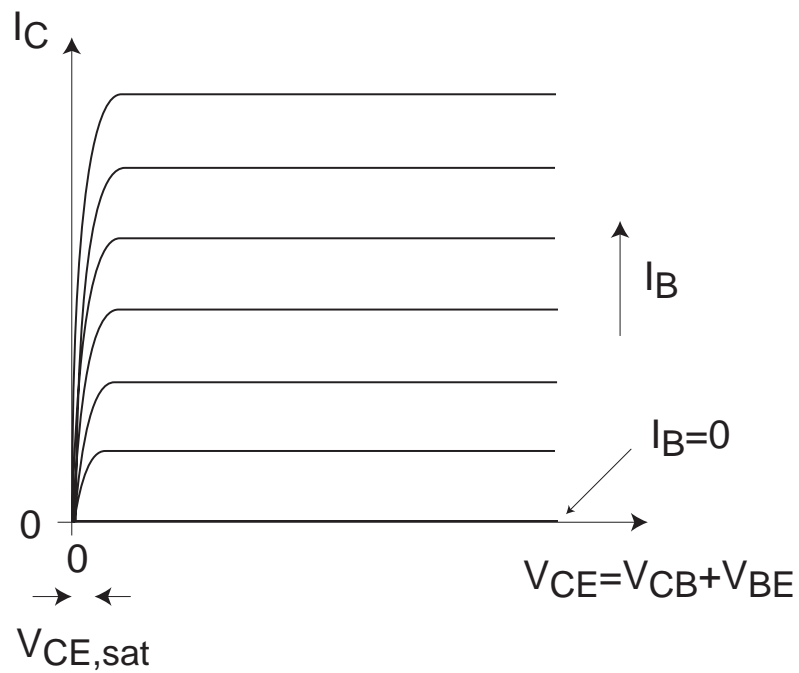
- **Cut-off regime:** $V_{BE} < 0$, $V_{BC} < 0$



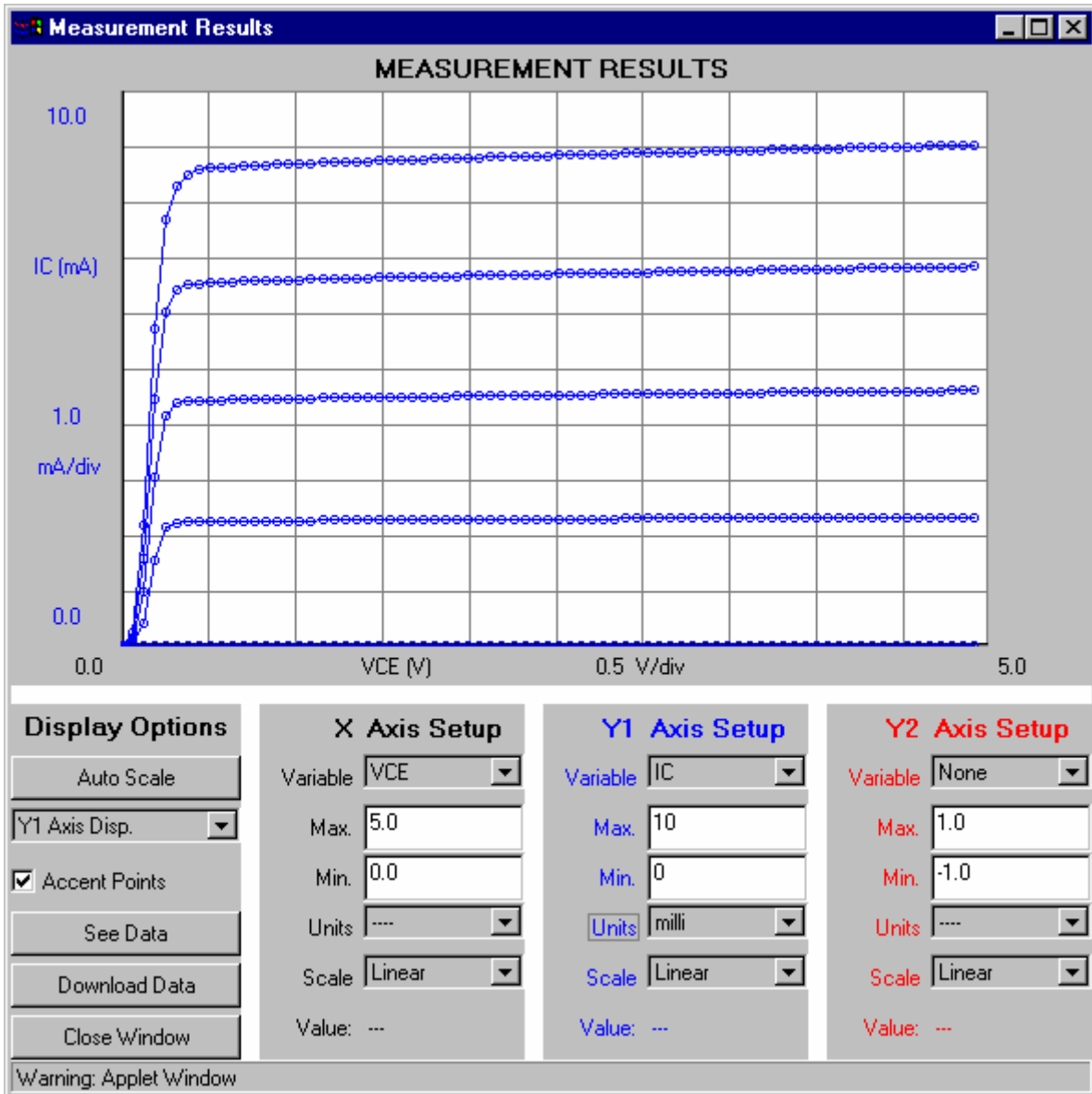
Only negligible leakage currents.

3. Output Characteristics

Common-emitter output characteristics:



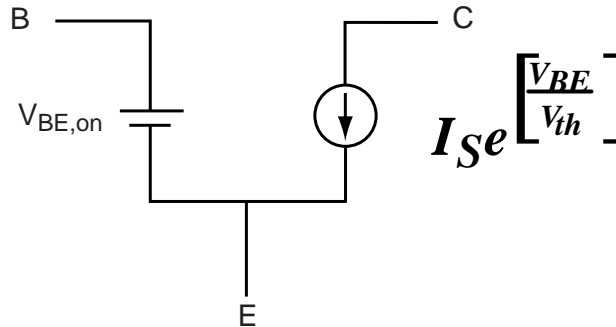
Common-Emitter Output Characteristics



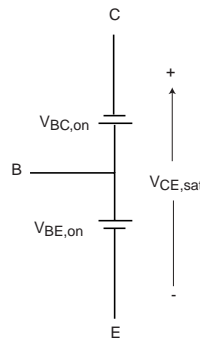
What did we learn today?

Summary of Key Concepts

- *Forward-active regime*: For bias calculations:



- *Saturation Regime*: For bias calculations:



- *Cut-off Regime*: For bias calculations:

